

# Maruf A Bhuiyan

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/9437689/publications.pdf>

Version: 2024-02-01

7  
papers

784  
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1683354

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1872312

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7  
docs citations

7  
times ranked

1851  
citing authors

| # | ARTICLE   | IF   | CITATIONS |
|---|---|------|-----------|
| 1 | Black Phosphorus Mid-Infrared Photodetectors with High Gain. Nano Letters, 2016, 16, 4648-4655.   | 4.5  | 616       |
| 2 | Synthesis of Crystalline Black Phosphorus Thin Film on Sapphire. Advanced Materials, 2018, 30, 1703748.   | 11.1 | 86        |
| 3 | Charge Trapping in Al <sub>2</sub> O <sub>3</sub> /SiO <sub>2</sub> -Ga <sub>2</sub> O <sub>3</sub> -Based MOS Capacitors. IEEE Electron Device Letters, 2018, 39, 1022-1025.                     | 2.2  | 50        |
| 4 | Total-Ionizing-Dose Responses of GaN-Based HEMTs With Different Channel Thicknesses and MOSHEMTs With Epitaxial MgCaO as Gate Dielectric. IEEE Transactions on Nuclear Science, 2018, 65, 46-52.  | 1.2  | 12        |
| 5 | Total Ionizing Dose (TID) Effects in Ultra-Thin Body Ge-on-Insulator (GOI) Junctionless CMOSFETs With Recessed Source/Drain and Channel. IEEE Transactions on Nuclear Science, 2017, 64, 176-180. | 1.2  | 10        |
| 6 | A Study of BEOL Processed Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> -based Ferroelectric Capacitors and Their Potential for Automotive Applications. , 2020, , .                         |      | 6         |
| 7 | Total Ionizing Dose (TID) Effects in GaAs MOSFETs With La-Based Epitaxial Gate Dielectrics. IEEE Transactions on Nuclear Science, 2017, 64, 164-169.  | 1.2  | 4         |